Power MOSFET

30 V, 29 A, Single N–Channel, SO–8 Flat Lead

Features

- Low R_{DS(on)}
- Optimized Gate Charge
- Low Inductance SO-8 Package
- This is a Pb–Free Device

Applications

- Notebooks, Graphics Cards
- DC–DC Converters
- Synchronous Rectification

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit	
Drain-to-Source Voltage			V _{DSS}	30	V	
Gate-to-Source Voltage			V _{GS}	20	V	
Continuous Drain Current	Steady	Steady $T_A = 25^{\circ}C$		17	А	
(Note 1)	State	$T_A = 85^{\circ}C$		12		
	t ≤10 s	$T_A = 25^{\circ}C$		29		
Power Dissipation (Note 1)	Steady State			2.2	W	
	t ≤10 s			6.6		
Continuous Drain Current	O 1 I	$T_A = 25^{\circ}C$	Ι _D	11	А	
(Note 2)	Steady State	$T_A = 85^{\circ}C$		8.0		
Power Dissipation (Note 2)	Claire	$T_A = 25^{\circ}C$	PD	0.9	W	
Pulsed Drain Current $t_p = 10 \ \mu s$			I _{DM}	88	А	
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to 150	°C	
Source Current (Body Diode)			۱ _S	6.5	А	
	Single Pulse Drain-to-Source Avalanche Energy $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_{PK} = 29 \text{ A}, L = 1 \text{ mH}, R_G = 25 \Omega$)			430	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			ΤL	260	°C	

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	56.2	°C/W
Junction-to-Ambient – t \leq 10 s (Note 1)	$R_{\theta JA}$	19	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	141.1	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

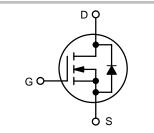
- 1. Surface mounted on FR4 board using 1 in sq pad size
- (Cu area = 1.127 in sq [1 oz] including traces).
- Surface mounted on FR4 board using the minimum recommended pad size (Cu area = 1.0 in sq).

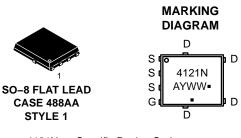


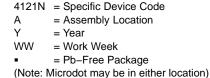
ON Semiconductor®

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V _{(BR)DSS}	R _{DS(on)} TYP	I _D MAX (Note 1)
30 V	4.0 mΩ @ 10 V	29 A
50 V	5.5 mΩ @ 4.5 V	23 A







ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFS4121NT1G	SO–8 FL (Pb–Free)	1500 Tape & Reel
NTMFS4121NT3G	SO–8 FL (Pb–Free)	5000 Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

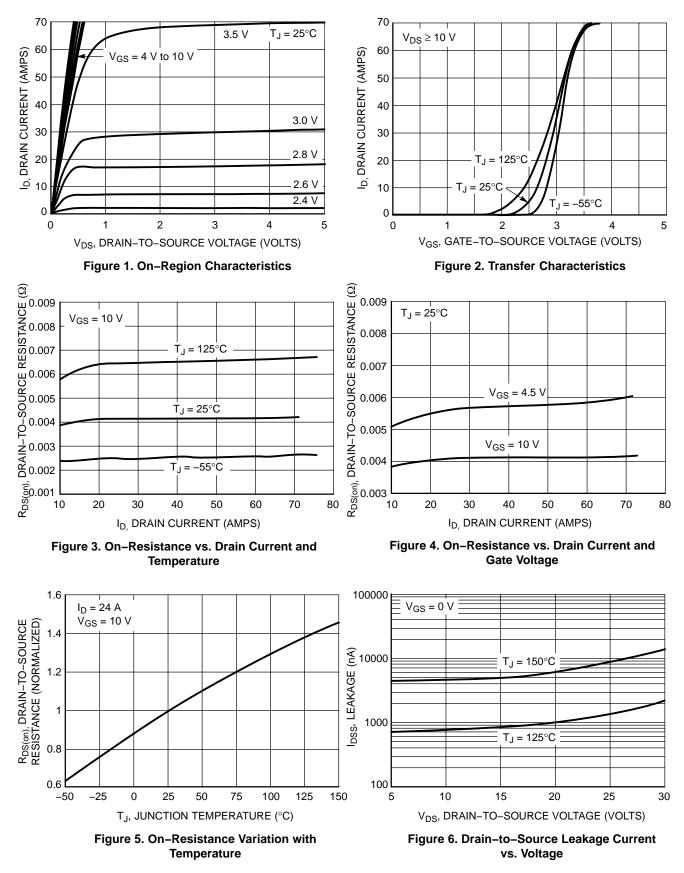
*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

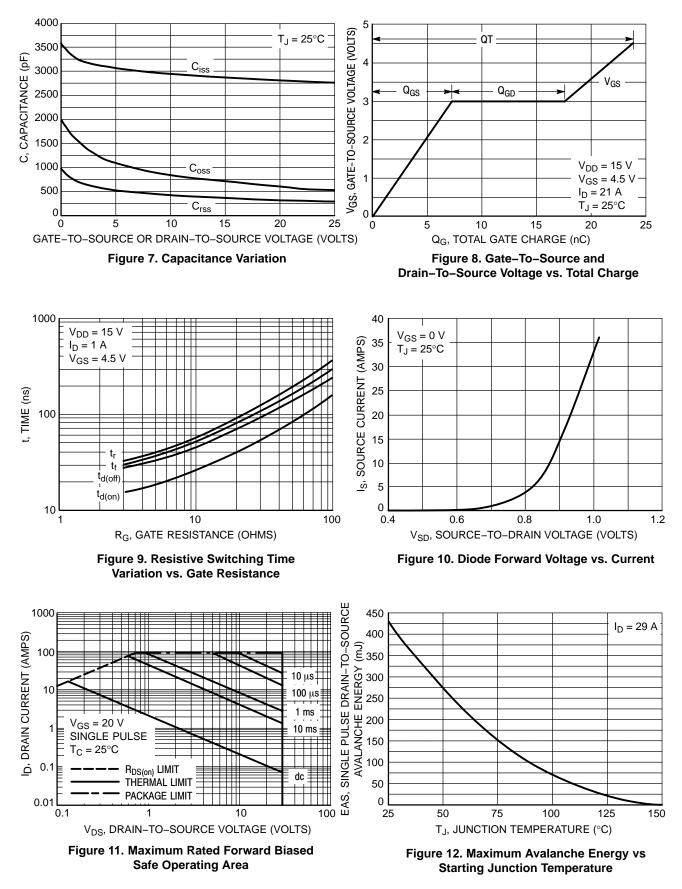
Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	-	•					-
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 V, I_D = 250 \mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				21		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	$T_J = 25^{\circ}C$			1.0	μA
		$v_{GS} = 0 v, v_{DS} = 24 v$	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS} =$	= 20 V			100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.0		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				7.4		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	= 24 A		4.2	5.25	mΩ
		V _{GS} = 4.5 V, I _D =	= 21 A		5.5	7.0	
Forward Transconductance	9 FS	V _{DS} = 15 V, I _D =	= 24 A		20		S
CHARGES, CAPACITANCES AND GATE R	ESISTANCE			-			
Input Capacitance	C _{ISS}				2700		pF
Output Capacitance	C _{OSS}	V_{GS} = 0 V, f = 1.0 MHz, V_{DS} = 24 V			480		
Reverse Transfer Capacitance	C _{RSS}				290		
Total Gate Charge	Q _{G(TOT)}	V_{GS} = 4.5 V, V_{DS} = 15 V, I_{D} = 21 A			24	40	nC
Threshold Gate Charge	Q _{G(TH)}				3.0		
Gate-to-Source Charge	Q _{GS}				7.3		
Gate-to-Drain Charge	Q _{GD}				10.2		1
Gate Resistance	R _G				1.5		Ω
SWITCHING CHARACTERISTICS, $V_{GS} = 4$.	5 V (Note 4)			-			-
Turn–On Delay Time	t _{d(ON)}				16		ns
Rise Time	tr	V _{GS} = 4.5 V, V _{DS} :	= 15 V.		29		
Turn–Off Delay Time	t _{d(OFF)}	$I_{\rm D} = 1.0 \text{ A}, \text{ R}_{\rm L} = 15 \Omega,$	$I_D = 1.0 \text{ A}, \text{ R}_L = 15 \Omega, \text{ R}_G = 3.0 \Omega$		32		1
Fall Time	t _f				31		
DRAIN-SOURCE DIODE CHARACTERISTI	cs						
Forward Diode Voltage	V _{SD}	$T_J = 25^{\circ}C$			0.8	1.0	V
		$V_{GS} = 0 V, I_{S} = 6.0 A$	T _J = 125°C		0.6		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 V, dI_S/dt = 100 A/\mu s,$ $I_S = 6.0 A$			34		ns
Charge Time	ta				18		1
Discharge Time	t _b				16		1
Reverse Recovery Charge	Q _{RR}				25.4		nC

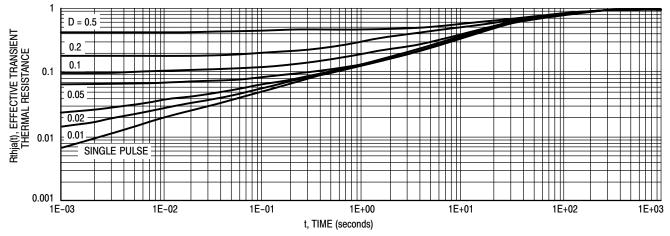
Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
Switching characteristics are independent of operating junction temperatures.





TYPICAL PERFORMANCE CURVES



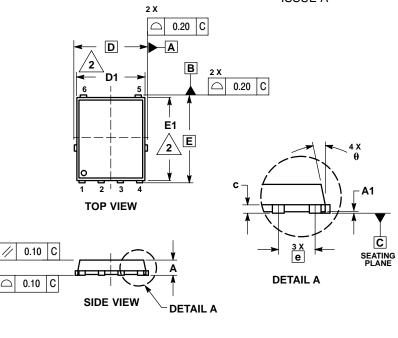




PACKAGE DIMENSIONS

SO-8 FLAT LEAD CASE 488AA-01

ISSUE A



DIMENSIONING AND TOLERANCING PER
ASME Y14.5M, 1994.
CONTROLLING DIMENSION: MILLIMETER.
DIMENSION D1 AND E1 DO NOT INCLUDE

NOTES

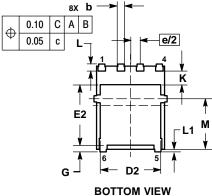
1.

 CONTROLLING DIMENSION: MILLIMETER.
DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS					
DIM	MIN	NOM	MAX			
Α	0.90	0.99	1.20			
A1	0.00		0.05			
b	0.33	0.41	0.51			
С	0.23	0.28	0.33			
D		5.15 BSC	;			
D1	4.50	4.90	5.10			
D2	3.50		4.22			
E	6.15 BSC					
E1	5.50	5.80	6.10			
E2	3.45		4.30			
е	1.27 BSC					
G	0.51	0.61	0.71			
К	0.51					
L	0.51	0.61	0.71			
L1	0.05	0.17	0.20			
М	3.00	3.40	3.80			
θ	0 °		12 °			

STYLE 1: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN

6. DRAIN



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